

# Michał, Tadeusiewicz

## List of Publications by Year in descending order

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61  
papers

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759233

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713466

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g-index

61  
all docs

61  
docs citations

61  
times ranked

157  
citing authors

#	ARTICLE	IF	CITATIONS
1	A Method for Parametric and Catastrophic Fault Diagnosis of Analog Linear Circuits. IEEE Access, 2022, 10, 27002-27013.	4.2	5
2	Parametric Fault Diagnosis of Very High-Frequency Circuits Containing Distributed Parameter Transmission Lines. Electronics (Switzerland), 2021, 10, 550.	3.1	3
3	A Method for Diagnosing Soft Short and Open Faults in Distributed Parameter Multiconductor Transmission Lines. Electronics (Switzerland), 2021, 10, 35.	3.1	4
4	Modeling Analysis and Diagnosis of Analog Circuits in z-Domain. Journal of Circuits, Systems and Computers, 2020, 29, 2050028.	1.5	0
5	Soft fault diagnosis of linear circuits with the special attention paid to the circuits containing current conveyors. AEU - International Journal of Electronics and Communications, 2020, 115, 153036.	2.9	2
6	Soft fault diagnosis of nonlinear circuits having multiple DC solutions. IET Circuits, Devices and Systems, 2020, 14, 1220-1227.	1.4	1
7	A method for fault diagnosis of nonlinear circuits. COMPEL - the International Journal for Computation and Mathematics in Electrical and Electronic Engineering, 2019, 38, 1770-1781.	0.9	1
8	A method for multiple soft fault diagnosis of linear analog circuits. Measurement: Journal of the International Measurement Confederation, 2019, 131, 714-722.	5.0	18
9	A Method for Local Parametric Fault Diagnosis of a Broad Class of Analog Integrated Circuits. IEEE Transactions on Instrumentation and Measurement, 2018, 67, 328-337.	4.7	36
10	Diagnosis of a soft short and local variations of parameters occurring simultaneously in analog CMOS circuits. Microelectronics Reliability, 2017, 72, 90-97.	1.7	3
11	A Systematic Method for Arranging Diagnostic Tests in Linear Analog DC and AC Circuits. Journal of Electronic Testing: Theory and Applications (JETTA), 2017, 33, 147-156.	1.2	4
12	Improvement of the search method for parametric fault diagnosis of analog integrated circuits. , 2016, , .		1
13	Diagnosis of Soft Spot Short Defects in Analog Circuits Considering the Thermal Behaviour of the Chip. Metrology and Measurement Systems, 2016, 23, 239-250.	1.4	3
14	Multiple soft fault diagnosis of DC analog CMOS circuits designed in nanometer technology. Analog Integrated Circuits and Signal Processing, 2016, 88, 65-77.	1.4	5
15	New Aspects of Fault Diagnosis of Nonlinear Analog Circuits. International Journal of Electronics and Telecommunications, 2015, 61, 83-93.	0.6	4
16	Spot Defect Diagnosis in Analog Nonlinear Circuits with Possible Multiple Operating Points. Journal of Electronic Testing: Theory and Applications (JETTA), 2015, 31, 491-502.	1.2	9
17	Catastrophic Fault Diagnosis of a Certain Class of Nonlinear Analog Circuits. Circuits, Systems, and Signal Processing, 2015, 34, 353-375.	2.0	16
18	A New Approach to Multiple Soft Fault Diagnosis of Analog BJT and CMOS Circuits. IEEE Transactions on Instrumentation and Measurement, 2015, 64, 2688-2695.	4.7	31

#	ARTICLE	IF	CITATIONS
19	Global and local parametric diagnosis of analog short-channel CMOS circuits using homotopy-simplicial algorithm. <i>International Journal of Circuit Theory and Applications</i> , 2014, 42, 1051-1068.	2.0	12
20	Numerical analysis of direct current circuits containing bipolar and metal oxide semiconductor transistors. <i>International Journal of Numerical Modelling: Electronic Networks, Devices and Fields</i> , 2014, 27, 935-948.	1.9	1
21	Multiple Soft Fault Diagnosis of Bjt Circuits. <i>Metrology and Measurement Systems</i> , 2014, 21, 663-674.	1.4	6
22	A Method for Finding Multiple DC Operating Points of Short Channel CMOS Circuits. <i>Circuits, Systems, and Signal Processing</i> , 2013, 32, 2457-2468.	2.0	8
23	A Very Fast Method for the DC Analysis of Diode-Transistor Circuits. <i>Circuits, Systems, and Signal Processing</i> , 2013, 32, 433-451.	2.0	16
24	Multiple Soft Fault Diagnosis of Nonlinear Circuits Using the Continuation Method. <i>Journal of Electronic Testing: Theory and Applications (JETTA)</i> , 2012, 28, 487-493.	1.2	10
25	Analysis of BJT circuits having multiple DC solutions using deflation technique. , 2012, , .		3
26	A Contraction Method for Locating All the DC Solutions of Circuits Containing Bipolar Transistors. <i>Circuits, Systems, and Signal Processing</i> , 2012, 31, 1159-1166.	2.0	13
27	Multiple catastrophic fault diagnosis of analog circuits considering the component tolerances. <i>International Journal of Circuit Theory and Applications</i> , 2012, 40, 1041-1052.	2.0	25
28	Multiple Soft Fault Diagnosis of Nonlinear DC Circuits Considering Component Tolerances. <i>Metrology and Measurement Systems</i> , 2011, 18, 349-360.	1.4	9
29	Analysis of transistor circuits having multiple DC solutions with the thermal constraint. <i>COMPEL - the International Journal for Computation and Mathematics in Electrical and Electronic Engineering</i> , 2011, 30, 1350-1362.	0.9	1
30	A method for fast simulation of multiple catastrophic faults in analogue circuits. <i>International Journal of Circuit Theory and Applications</i> , 2010, 38, 275-290.	2.0	7
31	Some Contraction Methods for Locating and Finding All the DC Operating Points of Diode-Transistor Circuits. <i>International Journal of Electronics and Telecommunications</i> , 2010, 56, 331-338.	0.5	7
32	Improved algorithm for computing all the DC operating points of diode-transistor circuits. , 2009, , .		1
33	Multiple catastrophic fault diagnosis of linear circuits considering the component tolerances. , 2009, , .		6
34	An efficient method for simulation of multiple catastrophic faults. , 2008, , .		6
35	Tracing some temperature characteristics in diode-transistor circuits having multiple DC solutions. , 2008, , .		0
36	Multiple soft fault diagnosis of analogue electronic circuits. , 2008, , .		5

#	ARTICLE	IF	CITATIONS
37	A method for multiple fault diagnosis in dynamic analogue circuits. , 2007, , .		7
38	Finding all the DC solutions of transistor circuits with the thermal constraint. , 2007, , .		2
39	A method for the analysis of transistor circuits having multiple DC solutions. AEU - International Journal of Electronics and Communications, 2006, 60, 582-589.	2.9	12
40	An algorithm for multiple fault diagnosis in analogue circuits. International Journal of Circuit Theory and Applications, 2006, 34, 607-615.	2.0	41
41	Transient analysis of nonlinear dynamic circuits using a numericalâ€ integration method. COMPEL - the International Journal for Computation and Mathematics in Electrical and Electronic Engineering, 2005, 24, 707-719.	0.9	2
42	Tracing AMâ€ detector transfer characteristics. COMPEL - the International Journal for Computation and Mathematics in Electrical and Electronic Engineering, 2005, 24, 1439-1449.	0.9	0
43	Computing Multivalued Inputâ€ Output Characteristics in the Circuits Containing Bipolar Transistors. IEEE Transactions on Circuits and Systems Part 1: Regular Papers, 2004, 51, 1859-1867.	0.1	8
44	An algorithm for soft-fault diagnosis of linear and nonlinear circuits. IEEE Transactions on Circuits and Systems Part 1: Regular Papers, 2002, 49, 1648-1653.	0.1	80
45	Global and local stability of circuits containing MOS transistors. IEEE Transactions on Circuits and Systems Part 1: Regular Papers, 2001, 48, 957-966.	0.1	17
46	A method for identification of asymptotically stable equilibrium points of a certain class of dynamic circuits. IEEE Transactions on Circuits and Systems Part 1: Regular Papers, 1999, 46, 1101-1109.	0.1	12
47	Finding all the DC solutions of a certain class of piecewise-linear circuits. Circuits, Systems, and Signal Processing, 1999, 18, 89-110.	2.0	3
48	Improvement of the sign test for finding all the DC solutions of piecewise-linear circuits. International Journal of Circuit Theory and Applications, 1998, 26, 531-538.	2.0	6
49	Stability analysis of equilibrium states of a certain class of nonâ€ linear dynamic circuits. COMPEL - the International Journal for Computation and Mathematics in Electrical and Electronic Engineering, 1998, 17, 741-748.	0.9	2
50	DC analysis of circuits with idealized diodes considering reverse bias breakdown phenomenon. IEEE Transactions on Circuits and Systems Part 1: Regular Papers, 1997, 44, 312-326.	0.1	23
51	A CONTRACTION ALGORITHM FOR FINDING ALL THE DC SOLUTIONS OF PIECEWISE-LINEAR CIRCUITS. Journal of Circuits, Systems and Computers, 1994, 04, 319-336.	1.5	32
52	A method for finding bounds on all the DC solutions of transistor circuits. IEEE Transactions on Circuits and Systems Part 1: Regular Papers, 1992, 39, 557-564.	0.1	8
53	A method for finding bounds on the location of all the solutions of dc piecewiseâ€ linear circuits. International Journal of Circuit Theory and Applications, 1990, 18, 165-174.	2.0	9
54	An algorithm for generation of the nodal impedance matrix for networks containing mutually coupled inductors. International Journal of Electrical Power and Energy Systems, 1988, 10, 36-40.	5.5	2

#	ARTICLE	IF	CITATIONS
55	D.C. ANALYSIS OF PIECEWISE LINEAR NETWORKS USING THE GAUSS-SEIDEL METHOD. COMPEL - the International Journal for Computation and Mathematics in Electrical and Electronic Engineering, 1986, 5, 195-205.	0.9	2
56	The solvability and monotonical properties of a certain class of D.C. nonlinear networks. International Journal of Circuit Theory and Applications, 1984, 12, 133-144.	2.0	0
57	On the solvability and computation of D.C. transistor networks. International Journal of Circuit Theory and Applications, 1981, 9, 251-267.	2.0	4
58	An algorithm for finding all the DC solutions of short-channel MOS transistor circuits. , 0, , .		0
59	Multiple fault diagnosis in analogue circuits. , 0, , .		4
60	Analysis of diode-transistor circuits having multiple DC solutions. , 0, , .		1
61	Determining multi-valued input-output characteristics in the circuits containing bipolar transistors. , 0, , .		1